

INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>	Docket Number (Optional) TWI-12410		Application Number 09/848,733
	Applicant(s) Craig Uhrich et al.		
	Filing Date May 3, 2001		Group Art Unit 2877

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE


FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

DS	CA	M.E. El-Ghazzawi et al., "Spectroellipsometry characterization of directly bonded silicon-on-insulator structures," <i>Thin Solid Films</i> , Vol. 233 (1993), pp. 218-222.

Examiner 	Date Considered 4/21/04
Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	